

10/649,251

August 26, 2003

Gregory R. Hanson et al.

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2500940-991510 (UBAT1510)

**Examiner ·
Initials**

Cite
No.

Document Number

Publication Date
MM-DD-YYYY

Name of Patentee or Applicant of Cited Document

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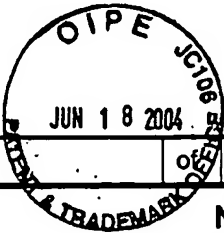
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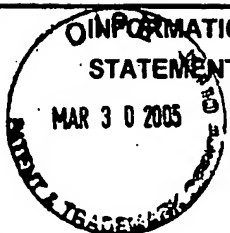
**Examiner
Signature**

PATRICK CONNOLLY

Date Considered

07.11.2005

INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		Application Number	10/649,251	
		Filing Date	August 26, 2003	
		First Named Inventor	Gregory R. Hanson	
		Group Art Unit	2621 2877	
		Examiner Name	Unknown Connolly	
Sheet 1	1	Attorney Docket Number	2500940-991510 (UBAT1510)	
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p7c	C2	Jacob et al., "High Resolution Photomask Transmission and Phase Measurement Tool", Metrology, Inspection and Process Control for Microlithography XVI, Proceedings of SPIE Vol. 4689, pp. 70-82, 2002.		
p7c	C3	Thomas et al., "Direct to Digital Holography for Semiconductor Wafer Defect Detection and Review", Design, Process Integration, and Characterization for Microelectronics, Proceedings of SPIE Vol. 4692, pp. 180-194, 2002.		
p7c	C4	"Phase Contrast Microscopy" Authors unknown, date unknown		
Examiner Signature	PATRICK CONNOLLY		Date Considered	07-11-2005

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		Examiner Name		Unknown Connolly				
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Examiner Signature		PATRICK CONNOLLY			Date Considered		07.11.2005	